

PATENT ABSTRACTS OF JAPAN

(11)Publication number : 63-062343

(43)Date of publication of application : 18.03.1988

(51)Int.Cl.

H01L 21/66

G01R 1/073

G01R 31/26

(21)Application number : 61-208173

(71)Applicant : NEC CORP

(22)Date of filing : 03.09.1986

(72)Inventor : NAKAO HIROSHI

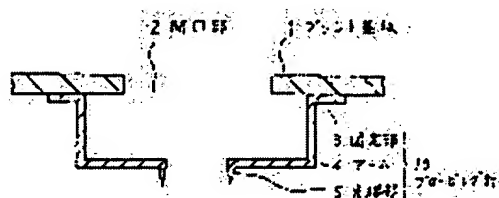
(54) PROBE CARD

(57)Abstract:

PURPOSE: To prevent displacement of a contact point, by providing a probing needle which comprises a fixed part mounted securely on a printed board, an L-shaped arm having one end connected securely to the fixing point, and a tip part connected securely to the other end of the arm and protruding downward.

CONSTITUTION: A probing needle 10 is composed of the following parts: a fixed part 3, which is fixed to a printed board 1 and connected to a conductor wire by way of through hole and the like; an L-shaped arm, whose one end is fixed to the fixing part 3; and a tip part 5, which is fixed to the other end of the arm and protrudes downward.

When the tip part 5 is brought into contact with the electrode of a semiconductor element at a specified needle pressure, the pressure applied on the tip part 5 is absorbed mainly by the elasticity of the L-shaped arm 4. Therefore, the tip part 5 may moved vertically, but will not deviate horizontally. This allows the electrodes on a semiconductor element to be made small.



LEGAL STATUS

[Date of request for examination]

BEST AVAILABLE COPY

[Date of sending the examiner's decision of

拒絶

rejection]

[Kind of final disposal of application other than
the examiner's decision of rejection or
application converted registration]

[Date of final disposal for application]

[Patent number]

[Date of registration]

[Number of appeal against examiner's
decision of rejection]

[Date of requesting appeal against examiner's
decision of rejection]

[Date of extinction of right]

Copyright (C); 1998,2003 Japan Patent Office